

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10614737	HICKS ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	ALLAHYAR KASRAIAN	2617

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
370	401	09/11/2007	AK
370	328	09/11/2007	AK
455	465	09/11/2007	AK

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST Image and keyword search in USPTO, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (see attached search strategy)	09/11/2007	AK
Inventor name and Assignee search in PALM_ExPo and EAST	09/11/2007	AK
IEEE Xplore: <a href="http://ieeexplore.ieee.org/Xplore/DynWel.jsp">http://ieeexplore.ieee.org/Xplore/DynWel.jsp</a>	09/11/2007	AK
Google: <a href="http://www.google.com">http://www.google.com</a>	09/11/2007	AK
EPO Data base: <a href="http://ep.espacenet.com">http://ep.espacenet.com</a>	09/11/2007	AK
Updated Search	3/26/2008	AK

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>